



TVRC Errata Item

1 Errata Item Details

Title	TCMT correction for the ICS-ID "T2T-SEC-SEL"
Certification Release(s) affected	CR11
TVRC Errata Item ID	TVRC-EE115
Date Received	2019-12-10
TVRC ID	EE115
Date Resolved	2020-01-29
CC/TWG Kavi Comment Reference	n/a
TWG Change Request (CR)	CR626

2 Document Details

TC Document Name	Test Case Mapping Table 3.0.00
TC Document Date	2018-03-08
TC Document Status	Published



3 Issue Summary

The ICS ID “T2T-SEC-SEL” shall not be part of a selection of a test case.

4 Issue Description

The ICS ID “T2T-SEC-SEL” shall not be part of the selection of the following test cases:

- TC_T2T_DYN_APP_READ_BV_5
- TC_T2T_DYN_APP_WRITE_BV_6
- TC_T2T_DYN_APP_TRANS_BV_7
- TC_T2T_DYN_APP_WRITE_RO_BI_8

5 Approved Resolution

A Dynamic Tag, with a memory size (in total) larger than 64 Bytes, but smaller than 1024 Bytes (i.e. single sector) of data without the need to support the sector select command (T2T-SEC-SEL), shall be tested (if other the features below are applicable). In each test case, it’s the LT that employs the sector select command in case the TLV area exceeds one sector.

Solution: Remove T2T-SEC-SEL in the TCMT for the four test case selections below.

NFC Forum TC name	NFC Forum TC reference	Selection (informative)	Test Configuration function (informative)	The test is performed if the following is true	Comments	PATTERN NUMBER
NDEF Read from Dynamic Memory Layout T2T	TC_T2T_DYN_APP_READ_BV_5			LTD-NFCA and (L-NFCA-NC-NFCID1-SS or L-NFCA-NC-NFCID1-DS or L-NFCA-NC-NFCID1-TS or L-NFCA-NC-NFCID1-DG) and T2T-CAP and T2T-MV-1.0 and T2T-MEM-DYN and T2T-SEC-SEL		N/A



T2T NDEF Write and Dynamic Memory Layout	TC_T2T_DYN_APP_WRITE_BV_6			LTD-NFCA and (L-NFCA-NC-NFCID1-SS or L-NFCA-NC-NFCID1-DS or L-NFCA-NC-NFCID1-TS or L-NFCA-NC-NFCID1-DG) and T2T-CAP and T2T-MV-1.0 and T2T-MEM-DYN and (T2T-WRITE and (NDEF-INIT or NDEF-R/W)) and T2T-SEC-SEL		N/A
T2T State Transition test and Dynamic Memory Layout	TC_T2T_DYN_APP_TRANS_BV_7			LTD-NFCA and (L-NFCA-NC-NFCID1-SS or L-NFCA-NC-NFCID1-DS or L-NFCA-NC-NFCID1-TS or L-NFCA-NC-NFCID1-DG) and T2T-CAP and T2T-MV-1.0 and T2T-MEM-DYN and T2T-WRITE and NDEF-R/W and T2T-SEC-SEL		N/A
NDEF Write in a READ ONLY Dynamic Memory Layout T2T	TC_T2T_DYN_APP_WRITE_RO_BI_8			LTD-NFCA and (L-NFCA-NC-NFCID1-SS or L-NFCA-NC-NFCID1-DS or L-NFCA-NC-NFCID1-TS or L-NFCA-NC-NFCID1-DG) and T2T-CAP and T2T-MV-1.0 and T2T-MEM-DYN and NDEF-RO and T2T-SEC-SEL		N/A

6 Document Updates to be Applied

[Test Case Mapping Table \(version 3.0.00\)](#)

7 Information to the Authorized Labs

Follow the instructions above when creating a test plan for Type 2 Tags.

8 Information to the CA

n/a



9 Information to the Validation House

n/a